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LABORATORY LOCATION/	NSF Engineering Sdn. Bhd.		
CENTRAL OFFICE:	PLO 819A, Jalan Platinum 4, Platinum Business Park, Kawasan		
	Perindustrian Pasir Gudang, Zon 12B, , 81700,		
	JOHOR		
	MALAYSIA		
SEPTEMBER PRO			
ACCREDITED SINCE :	06 APRIL 2025		
FIELD(S) OF TESTING:	MECHANICAL		
FIELD(S) OF CALIBRATION:	ELECTRICAL		
	PRESSURE		
	TEMPERATURE		

This laboratory has demonstrated its technical competence to operate in accordance with MS ISO/IEC 17025:2017 (ISO/IEC 17025:2017).

This laboratory's fulfillment of the requirements of ISO/IEC 17025 means the laboratory meets both the technical competence requirements and management system requirements that are necessary for it to consistently deliver technically valid test results and calibrations. The management system requirements in ISO/IEC 17025 are written in language relevant to laboratory operations and operate generally in accordance with the principles of ISO 9001 (see Joint ISO-ILAC-IAF Communiqué dated April 2017).

* The uncertainty covered by the CMC is expressed as the expanded uncertainty corresponding to a coverage probability of approximately 95 % and have a coverage factor of k=2 unless stated otherwise.

	NSF Engineering Sdn. Bhd. PLO 819A, Jalan Platinum 4, Platinum Business Park, Kawasan Perindustrian Pasir Gudang, Zon 12B, , 81700, Johor
FIELD(S) OF TESTING:	MECHANICAL,

SCOPE OF TESTING: MECHANICAL

Material / Product Tested	Type Of Test / Properties Measured / Range Of Measurement	Standard Test Methods / Equipment / Techniques		
CENTRAL LOCATION	·	PLO 819A, Jalan Platinum 4, Platinum Business Park, Kawasan Perindustrian Pasir Gudang, Zon 12B, , 81700,		
FIELD(S) OF CALIBRATION:	ELECTRICAL, PRESSURE, I	HEAT & TEMPERATURE		

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SCOPE OF CALIBRATION: ELECTRICAL

Instrument Calibrated/Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty (±)*	Remarks
Measuring Instruments (dc Voltage)	0 mV to 330 mV 330 mV to 3.3 V 3.3 V to 33 V 33 V to 330 V 330 V to 1000 V	22 mV/V + 1.6 mV 14 mV/V + 1.8 mV 14 mV/V + 48 mV 23 mV/V + 23 mV 21 mV/V + 2.2 mV Note: Apply EOS for onsite	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
Measuring Instrument (ac Voltage)	33 mV to 750 V	See Matrix D Note: Apply EOS for onsite.	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
	Range / Frequency 33 mV to 330 mV 330 mV to 3.3 V 3.3 V to 33 V 33 V to 330 V 330 V to 750 V	10 Hz to 45 Hz 0.33 mV / V 0.32 mV / V 0.34 mV / V	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
Measuring Instrument (dc Current)	0 mA to 330 mA 330 mA to 3.3 mA 3.3 mA to 330 mA 330 mA to 1.1 A 1.1 A to 3 A 3 A to 10 A	0.17 nA / A + 23 nA 0.11 mA / A + 57 mA 0.11 mA / A + 0.29 mA 0.11 mA / A + 2.9 mA 0.23 mA / A + 47 mA 0.43 mA / A + 46 mA 0.57 mA / A + 0.57 mA Note: Apply EOS for onsite.	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)

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Instrument Calibrated/Measurement Parameter	Range	Calibration and Measurement Capability Expressed as an Uncertainty (±)*	Remarks
Measuring Instrument (ac Current)	33 mA to 10 A	See Matrix E Note: Apply EOS for onsite.	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)
	Range / Frequency 33 mA to 330 mA 330 mA to 3.3 mA 3.3 mA to 33 mA 330 mA to 1.1 A 1.1 A to 3 A 3 A to 10 A	10 Hz to 20 Hz	Generate using Fluke 5522A based on EURAMET cg-15, Version 3 (02/2015)

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SCOPE OF CALIBRATION: PRESSURE

Instrument	Range	Calibration and	Remarks
Calibrated/Measurement		Measurement	
Parameter		Capability	
		Expressed as an	
		Uncertainty (+)*	

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SCOPE OF CALIBRATION: TEMPERATURE

Instrument	Range	Calibration and	Remarks
Calibrated/Measurement		Measurement	
Parameter		Capability	
		Expressed as an	
		Uncertainty (±)*	